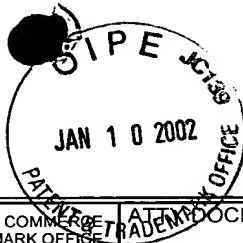




Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 214935US2PCT		SERIAL NO. 09/926,335	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hiroyuki FUKADA			
				FILING DATE October 23, 2001		GROUP 2681	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
S.A.	AO	9-135215	05/20/97	JAPAN (with partial English translation)			X
S.A.	AP	1 096 711	05/02/2001	EUROPE			
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>Shaina A. Amis</i>				Date Considered <i>3-2-04</i>			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTORNEY DOCKET NO. 214935US2PCT		SERIAL NO. 09/926,335	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hiroyuki FUKADA			
				FILING DATE October 23, 2001		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
S.A.	AO	WO 2000-02338	01/13/2000	WIPO			
	AP	1225529	08/11/99	CHINA			
	AQ	8-79161	03/22/96	JAPAN (submitting English Abstract only)			
	AR	8-223108	08/30/96	JAPAN (with English Abstract)			X
	AS	9-135215	05/20/97	JAPAN (with English Abstract)			X
	AT	11-220774	08/10/99	JAPAN (with English Abstract)			X
S.A.	AU	2000-22665	01/21/2000	JAPAN (with English Abstract)			X
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						
Examiner <i>Shaina R. Chinn</i>					Date Considered <i>3-2-04</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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